SCLS107C - DECEMBER 1982 - REVISED MAY 1997

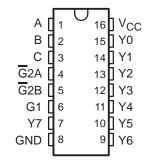
- Designed Specifically for High-Speed Memory Decoders and Data Transmission Systems
- Incorporate Three Enable Inputs to Simplify Cascading and/or Data Reception
- Package Options Include Plastic Small-Outline (D), Thin Shrink Small-Outline (PW), and Ceramic Flat (W) Packages, Ceramic Chip Carriers (FK), and Standard Plastic (N) and Ceramic (J) 300-mil DIPs

#### description

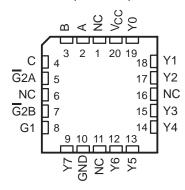
The 'HC138 are designed to be used in high-performance memory-decoding or datarouting applications requiring very short propagation delay times. In high-performance memory systems, these decoders can be used to minimize the effects of system decoding. When employed with high-speed memories utilizing a fast enable circuit, the delay times of these decoders and the enable time of the memory are usually less than the typical access time of the memory. This means that the effective system delay introduced by the decoders is negligible.

The conditions at the binary-select inputs at the three enable inputs select one of eight output lines. Two active-low and one active-high enable inputs reduce the need for external gates or inverters when expanding. A 24-line decoder can be implemented without external inverters and a 32-line decoder requires only one inverter. An enable input can be used as a data input for demultiplexing applications.

SN54HC138 . . . J OR W PACKAGE SN74HC138 . . . D, N, OR PW PACKAGE (TOP VIEW)



SN54HC138 . . . FK PACKAGE (TOP VIEW)



NC - No internal connection

The SN54HC138 is characterized for operation over the full military temperature range of –55°C to 125°C. The SN74HC138 is characterized for operation from –40°C to 85°C.



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

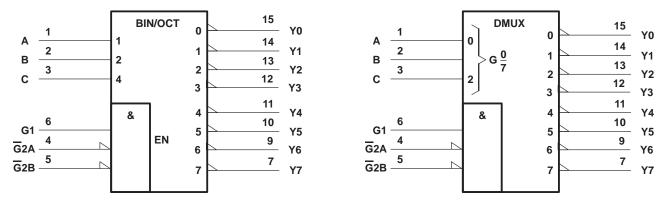


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#### **FUNCTION TABLE**

		INP	JTS			OUTPUTS							
	ENABLE	Ē	,	SELECT	•								
G1	G2A	G2B	С	В	Α	Y0	Y1	Y2	Y3	Y4	Y5	Y6	Y7
Х	Н	Х	Х	Х	Х	Н	Н	Н	Н	Н	Н	Н	Н
Х	X	Н	Х	X	X	Н	Н	Н	Н	Н	Н	Н	Н
L	X	X	Х	Χ	Χ	Н	Н	Н	Н	Н	Н	Н	Н
Н	L	L	L	L	L	L	Н	Н	Н	Н	Н	Н	Н
Н	L	L	L	L	Н	Н	L	Н	Н	Н	Н	Н	Н
Н	L	L	L	Н	L	Н	Н	L	Н	Н	Н	Н	Н
Н	L	L	L	Н	Н	Н	Н	Н	L	Н	Н	Н	Н
Н	L	L	Н	L	L	Н	Н	Н	Н	L	Н	Н	Н
н	L	L	Н	L	Н	Н	Н	Н	Н	Н	L	Н	Н
Н	L	L	Н	Н	L	Н	Н	Н	Н	Н	Н	L	Н
Н	L	L	Н	Н	Н	Н	Н	Н	Н	Н	Н	Н	L

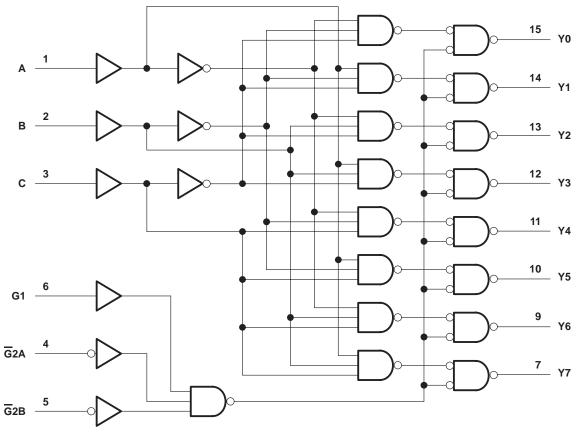
### logic symbols (alternatives)†



<sup>&</sup>lt;sup>†</sup> These symbols are in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12. Pin numbers shown are for the D, J, N, PW, and W packages.



#### logic diagram (positive logic)



Pin numbers shown are for the D, J, N, PW, and W packages.

## absolute maximum ratings over operating free-air temperature range†

Supply voltage range, V <sub>CC</sub>	0.5 V to 7 V
Input clamp current, $I_{IK}$ ( $V_I < 0$ or $V_I > V_{CC}$ ) (see Note	l) ±20 mA
Output clamp current, IOK (VO < 0 or VO > VCC) (see N	lote 1) ±20 mA
Continuous output current, $I_O(V_O = 0 \text{ to } V_{CC})$	±25 mA
Continuous current through V <sub>CC</sub> or GND	
Package thermal impedance, $\theta_{JA}$ (see Note 2): D pack	
N pack	age 78°C/W
PW pa	ckage 149°C/W
Storage temperature range, T <sub>stq</sub>	–65°C to 150°C

<sup>†</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

2. The package thermal impedance is calculated in accordance with JESD 51, except for through-hole packages, which use a trace length of zero.



# SN54HC138, SN74HC138 3-LINE TO 8-LINE DECODERS/DEMULTIPLEXERS

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#### recommended operating conditions

			SI	SN54HC138			SN74HC138			
			MIN	NOM	MAX	MIN	NOM	MAX	UNIT	
Vсс	Supply voltage		2	5	6	2	5	6	V	
		V <sub>CC</sub> = 2 V	1.5			1.5				
VIH	High-level input voltage	V <sub>CC</sub> = 4.5 V	3.15			3.15			V	
		V <sub>CC</sub> = 6 V	4.2			4.2				
		V <sub>CC</sub> = 2 V	0		0.5	0		0.5		
٧ <sub>IL</sub>	Low-level input voltage	V <sub>CC</sub> = 4.5 V	0		1.35	0		1.35	V	
		V <sub>CC</sub> = 6 V	0		1.8	0		1.8		
VI	Input voltage		0		VCC	0		VCC	V	
٧o	Output voltage		0		VCC	0		VCC	V	
		V <sub>CC</sub> = 2 V	0		1000	0		1000		
t <sub>t</sub>	Input transition (rise and fall) time	$V_{CC} = 4.5 \text{ V}$	0		500	0		500	ns	
		V <sub>CC</sub> = 6 V	0		400	0		400		
TA	Operating free-air temperature		-55		125	-40		85	°C	

# electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS		V	T <sub>A</sub> = 25°C			SN54HC138		SN74HC138		UNIT
PARAMETER	1231 CC	vcc	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT	
			2 V	1.9	1.998		1.9		1.9		
		I <sub>OH</sub> = -20 μA	4.5 V	4.4	4.499		4.4		4.4		
Voн	VI = VIH or VIL		6 V	5.9	5.999		5.9		5.9		V
		$I_{OH} = -4 \text{ mA}$	4.5 V	3.98	4.3		3.7		3.84		
		$I_{OH} = -5.2 \text{ mA}$	6 V	5.48	5.8		5.2		5.34		
	VI = VIH or VIL	Ι <sub>ΟL</sub> = 20 μΑ	2 V		0.002	0.1		0.1		0.1	V
			4.5 V		0.001	0.1		0.1		0.1	
VOL			6 V		0.001	0.1		0.1		0.1	
		I <sub>OL</sub> = 4 mA	4.5 V		0.17	0.26		0.4		0.33	
		I <sub>OL</sub> = 5.2 mA	6 V		0.15	0.26		0.4		0.33	
lį	$V_I = V_{CC}$ or 0		6 V		±0.1	±100		±1000		±1000	nA
<sup>I</sup> CC	$V_I = V_{CC}$ or 0,	I <sub>O</sub> = 0	6 V			8		160		80	μΑ
C <sub>i</sub>			2 V to 6 V		3	10		10		10	pF

# switching characteristics over recommended operating free-air temperature range, $C_L = 50 \text{ pF}$ (unless otherwise noted) (see Figure 1)

PARAMETER	FROM TO		V	T,	T <sub>A</sub> = 25°C			IC138	SN74HC138		UNIT		
PARAMETER	(INPUT)	(OUTPUT)	VCC	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNII		
		Any Y	2 V		67	180		270		225			
	A, B, or C		4.5 V		18	36		54		45			
<b>.</b> .			6 V		15	31		46		38	ns		
<sup>t</sup> pd	Enable	Any Y	2 V		66	155		235		195			
			4.5 V		18	31		47		39			
			6 V		15	26		40		33			
		Any			2 V		38	75		110		95	
t <sub>t</sub>			4.5 V		8	15		22		19	ns		
			6 V		6	13		19		16			

#### operating characteristics, T<sub>A</sub> = 25°C

	PARAMETER	TEST CONDITIONS	TYP	UNIT
C <sub>pd</sub>	Power dissipation capacitance	No load	85	pF

#### PARAMETER MEASUREMENT INFORMATION **VCC** From Output Test Input 50% 50% **Under Test Point** $C_L = 50 pF$ - tPHL (see Note A) ۷он In-Phase 90% 50% Output 10% V<sub>OL</sub> **LOAD CIRCUIT** 10% - tPHL Vон 90% 90% Input 90% **Out-of-Phase** Output **VOLTAGE WAVEFORM VOLTAGE WAVEFORMS INPUT RISE AND FALL TIMES** PROPAGATION DELAY AND OUTPUT TRANSITION TIMES

- NOTES: A. C<sub>L</sub> includes probe and test-fixture capacitance.
  - B. Phase relationships between waveforms were chosen arbitrarily. All input pulses are supplied by generators having the following characteristics: PRR  $\leq$  1 MHz,  $Z_O = 50 \ \Omega$ ,  $t_\Gamma = 6 \ ns$ ,  $t_f = 6 \ ns$ .
  - C. The outputs are measured one at a time with one input transition per measurement.
  - D. tpLH and tpHL are the same as tpd.

Figure 1. Load Circuit and Voltage Waveforms

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